

NAME

classall – general classification program

SYNOPSIS

classall [*dirname*]

DESCRIPTION

classall classifies all SIF files in MASTSIF or in the directory *dirname* given as an argument. The result of the classification is stored in the database file CLASSF.DB.

classall Options

You can start classall with the following options:

dirname

classifies all SIF files in *dirname*. If *dirname* is not specified, MASTSIF is searched.

ENVIRONMENT**SIFDECODE**

Parent directory for SIFDecode.

MASTSIF

A pointer to the directory containing the CUTest/SIFDecode problems collection.

AUTHORS

I. Bongartz, A.R. Conn, N.I.M. Gould, D. Orban and Ph.L. Toint

SEE ALSO

CUTest: a Constrained and Unconstrained Testing Environment with safe threads,
N.I.M. Gould, D. Orban and Ph.L. Toint,
Technical Report, Rutherford Appleton Laboratory, 2013.

CUTer (and SifDec): A Constrained and Unconstrained Testing Environment, revisited,
N.I.M. Gould, D. Orban and Ph.L. Toint,
ACM TOMS, **29**:4, pp.373-394, 2003.

CUTE: Constrained and Unconstrained Testing Environment,
I. Bongartz, A.R. Conn, N.I.M. Gould and Ph.L. Toint,
ACM TOMS, **21**:1, pp.123-160, 1995.

classify(1), select(1).

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